

Fabrication and Characterization of Electrical Discharge Machinable Si_3N_4 -TiN Composites

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Electrical discharge machinable Si_3N_4 was fabricated with the addition of 20-60 vol% TiN by gas pressure sintering. Their sinterability, microstructure, mechanical and electrical properties were characterized as a function of the TiN content. The addition of TiN up to 20 vol% increased the flexural strength and fracture toughness as compared with those of the monolithic Si_3N_4 . For the TiN content higher than 40 vol%, the electrical resistivity was lower than $10^2 \Omega \text{ cm}$. The Si_3N_4 with the addition of 40 vol% of TiN appears to have the optimum considerable sinterability, mechanical and electrical properties, and machinability. A microstructural analysis showed that the enhanced toughening was due to the crack deflection.

Key words : Si_3N_4 -TiN composites, Electrical discharge machinable ceramics

I. Introduction

Silicon nitride (Si_3N_4) is one of the most important engineering materials because of its excellent room and high temperature mechanical properties.¹⁾ However, Si_3N_4 is very difficult to machine because of its high hardness.

In order to find out inexpensive machining routes, electrical discharge machinable (EDM) Si_3N_4 ceramics have been fabricated by adding various conductive second phases such as carbides, nitrides or borides, or silicon carbide fibers.^{2,5)} Among these second phases, TiN is the most suitable material for EDM Si_3N_4 because of its high melting temperature, stiffness, hardness and electrical conductivity. Furthermore, addition of TiN improves mechanical properties of Si_3N_4 ceramics due to the reinforcing effect of TiN.^{2,6)}

In this study, EDM Si_3N_4 were prepared with the addition of 20, 40 and 60 vol% of TiN by gas pressure sintering. The effects of TiN content on the mechanical and electrical properties, and machinability were studied for an optimum EDM Si_3N_4 composition.

II. Experimental

A Si_3N_4 powder (E-10, Ube Industries, Tokyo, Japan) was mixed with 0-60 v/o TiN powder (Grade C, HCST, Berlin, Germany) and sintering additives in methanol using Si_3N_4 balls and a polyethylene jar. Sintering additives were 2 wt% Y_2O_3 (> 99.9%, Johnson Matthey Korea Ltd.) and 1 wt% Al_2O_3 (AKP30, Sumitomo Chemical Co., Tokyo, Japan). The mixed slurry was dried in an evaporator (WB2000, Heidolph, Germany) and sieved

through a 60 mesh screen. The powder was uniaxially pressed into a bar shape and cold isostatically pressed under 140 MPa. The green compacts were sintered at 1800°C under 2 MPa of nitrogen for 2 hrs followed by a second step 1900°C under 8 MPa of nitrogen for 2 hrs.

Densities were measured using the Archimedes method. Theoretical densities were calculated based on the rule of mixtures. Sintered specimens were cut and surface-ground using an 800 grit diamond wheel into $4 \times 3 \times 25$ mm bars. Four-point flexural strengths were measured at room temperature with the outer span of 20 mm and inner span of 8 mm. Fracture toughnesses were measured by the indentation method⁶⁾ with a load of 196 N. The samples were etched in molten NaOH for the observation of microstructures by a scanning electron microscopy (SEM). Foils were prepared by ion milling and the grain boundary phases were characterized by a transmission electron microscopy (TEM). The electrical conductivity was measured using a 4-point probe method. EDM was done using a wire electrode (Cu-30% Zn wire, 0.25 mm-diameter).

III. Results and Discussion

All compositions were sintered close to theoretical densities without difficulty (Table I).

Fig. 1 shows the microstructures of various Si_3N_4 -TiN composites prepared in this study. The elongate grains are Si_3N_4 , and the equiaxial grains are TiN. It shows clearly the role of TiN as grain growth inhibitor. Monolithic Si_3N_4 reveals large exaggerated grains among small columnar grains, which is typical of Si_3N_4 sintered with a

small amount of additives at relatively high temperatures.^{7,8)} With the addition of 20 vol% of TiN, abnormal grain growth is largely suppressed and a fairly uniform microstructure of columnar grains of Si_3N_4 is produced. With further addition of TiN, the TiN phase becomes the matrix and the growth of Si_3N_4 grain is completely ceased.

Fig. 2 shows TEM photomicrographs of the Si_3N_4 -40 vol% TiN composites. Glassy phases are found at triple junctions and Si_3N_4 -TiN interfaces eventhough small amount of additives were used in this study. This fea-

Table 1. Sintered Densities and Electrical Resistivities of the Si_3N_4 -TiN Composites.

Composition (vol%)	g/cm^3	Density % of theoretical density	Electrical resistivity (20°C, $\Omega\cdot\text{cm}$)
0	3.21	100	$> 10^{10}$
20	3.64	99.9	1.0×10^8
40	3.99	99.8	1.7×10^3
60	4.43	99.8	4.2×10^4

ture is almost identical to numerous observations found in Si_3N_4 ceramics.^{9,10)} It is expected, therefore, that the prepared samples would behave similarly to monolithic Si_3N_4 ceramics showing degradation of strength and creep at high temperatures which are caused by the liquid phase at grain boundaries.¹⁰⁻¹²⁾

Fig. 3 shows the flexural strength and fracture toughness of Si_3N_4 -TiN composites in terms of the TiN content. Both properties show their maxima at 20 vol% addition of TiN. These results can be explained by referring the microstructures shown in Fig. 1. For the monolithic Si_3N_4 , the large exaggerated grains of Si_3N_4 act as crack-initiating flaw (Fig. 4) resulting a relatively low strength.¹³⁾ With the addition of 20 vol% TiN, large exaggerated grains are disappeared and the processing-related flaws such as pores act as crack-initiating flaw (Fig. 4). Therefore, higher strength could be expected since the size of crack-initiating flaws are decreased from the large exaggerated grains to the small pores. Furthermore, uniform columnar grains of Si_3N_4 interlock each other making the material stronger and tougher. With further ad-

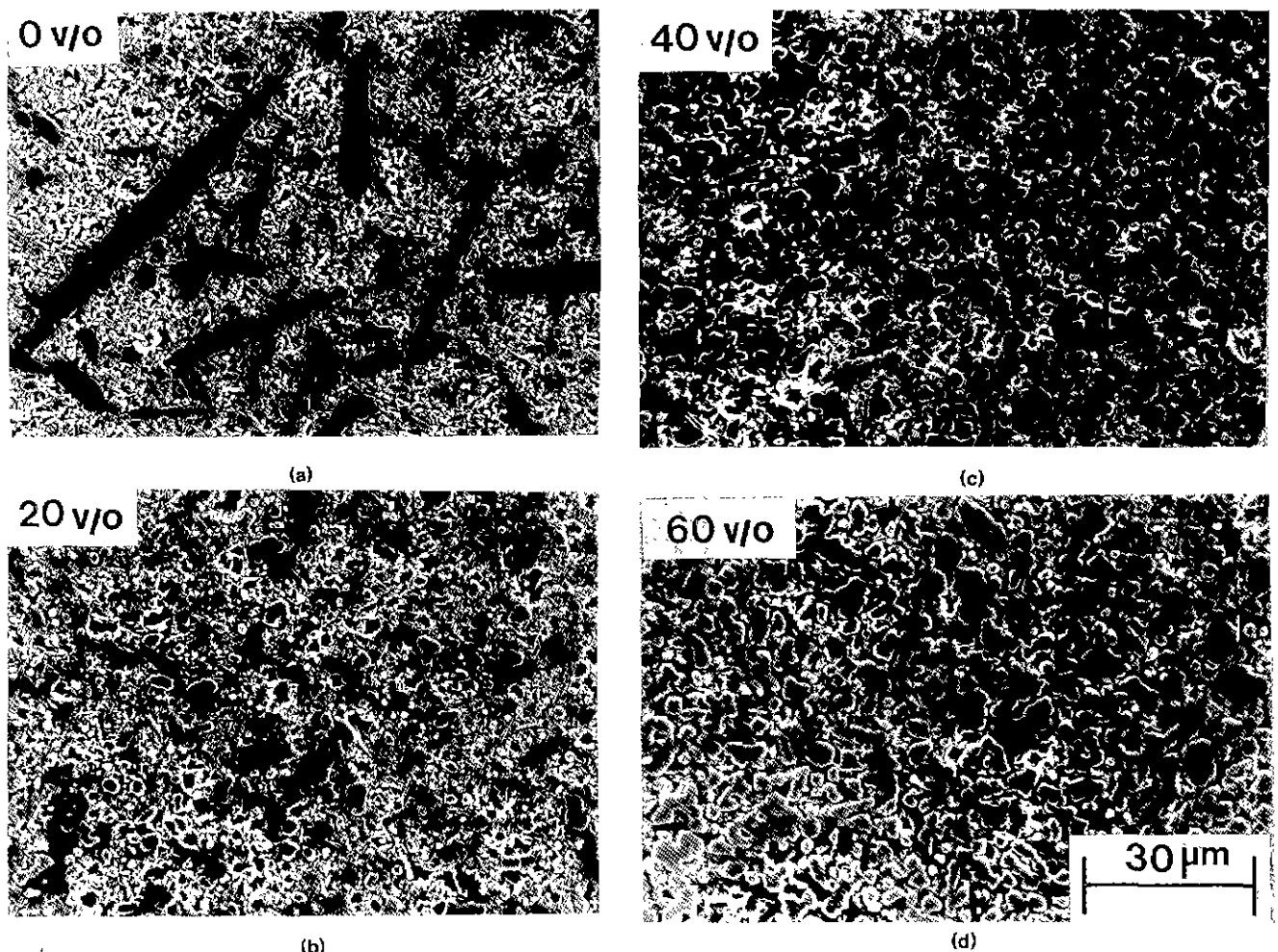


Fig. 1. Microstructures of the polished and etched surfaces of Si_3N_4 -TiN composites; (a) 0 v/o TiN, (b) 20 v/o TiN, (c) 40 v/o TiN and (d) 60 v/o.

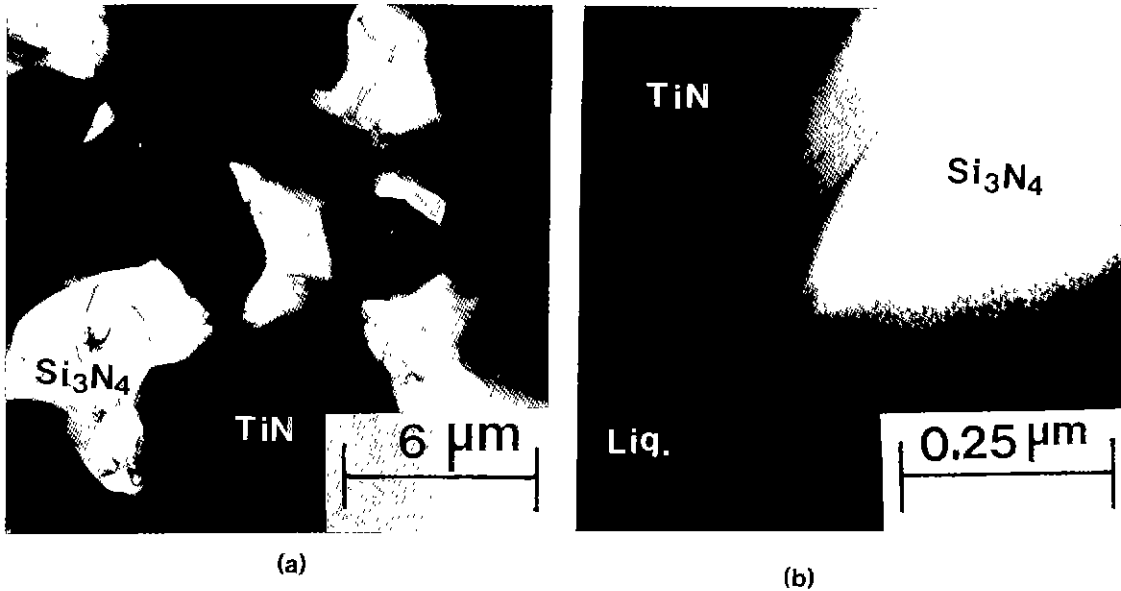


Fig. 2. TEM photomicrographs of Si₃N₄-40 vol% TiN composites showing liquid phase at triple junctons and Si₃N₄-TiN interfaces; (a) low magnification and (b) high magnification.

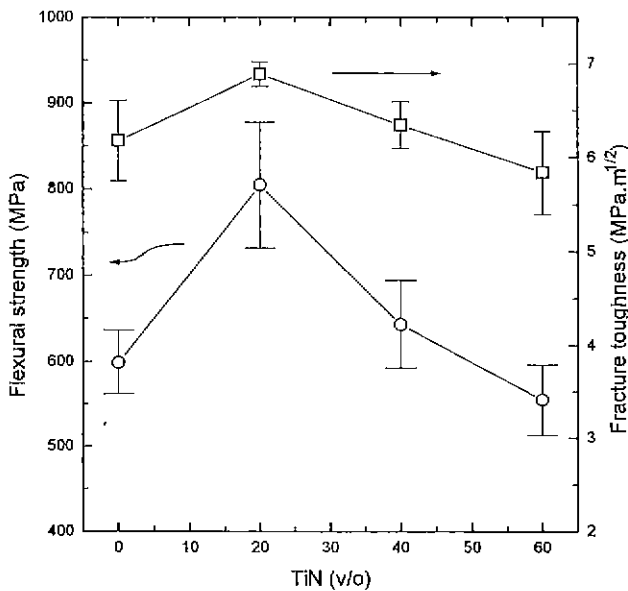


Fig. 3. Flexural strengths and fracture toughnesses of the Si₃N₄-TiN composites as a function of the TiN content.

dition of TiN, the toughening and strengthening effect of columnar Si₃N₄ grains do not exist since equiaxial TiN grains become the dominant phase.¹⁴⁾

Fig. 5 shows the change of crack propagating behaviors with the addition of TiN. In monolithic Si₃N₄, it can be seen that the large exaggerated grains of Si₃N₄ do not contribute to toughening by letting the crack go through (transgranular fracture mode). In Si₃N₄ with 20 vol% TiN, however, typical crack deflection by columnar Si₃N₄ and TiN grains takes place. Therefore, it is believed that the slightly higher fracture toughness shown at 20 vol% of

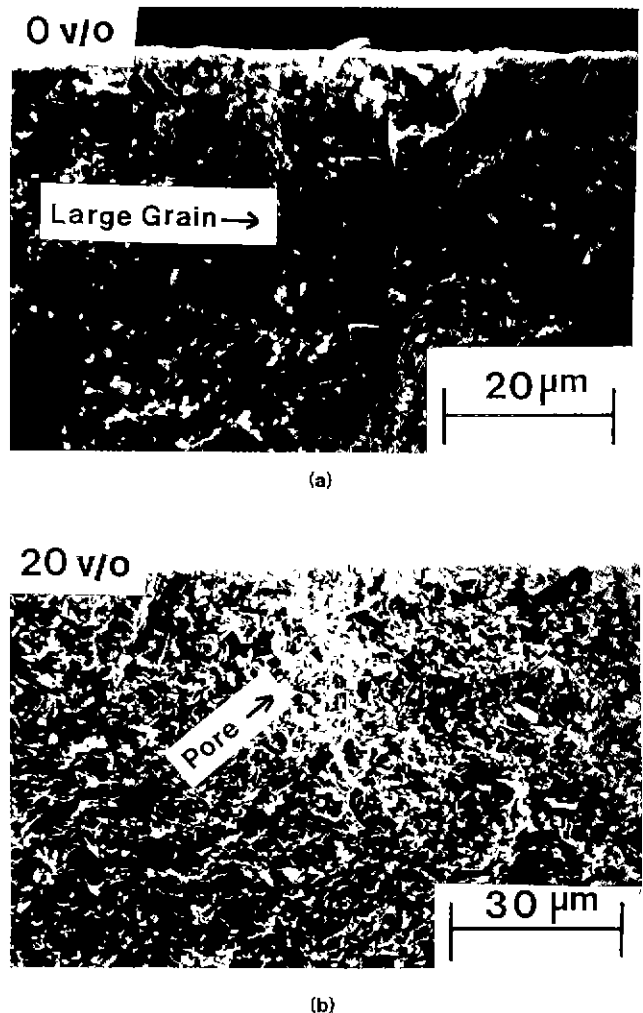


Fig. 4. Typical fracture origins of Si₃N₄-TiN composites; (a) 0 v/o TiN and (b) 20 v/o TiN

TiN is mainly due to the crack deflection by Si_3N_4 and TiN grains without transgranular fracture of large exaggerated grains. On the other hand, the lower fracture

toughness of monolithic Si_3N_4 is due to the transgranular fracture of large exaggerated grains.

The electrical resistivity of Si_3N_4 -TiN composites as a function of the TiN content is shown in Table I. As expected, the electrical resistivity is decreased with the amount of TiN. A material with a resistivity lower than $1 \Omega \cdot \text{cm}$ could be electrically discharge machined,¹⁵⁾ but a resistivity lower than $10^{-2} \Omega \cdot \text{cm}$ is preferred for Si_3N_4 for good machinability.³⁾ Tests showed that Si_3N_4 -40 vol% TiN composites (10 mm thick) could be cut at the rate of 10.2 mm/min and its average surface roughness (R_a) was 4.476 μm . The machined surface was covered by melted and oxidized products of Si_3N_4 and TiN (Fig. 6).

IV. Conclusion

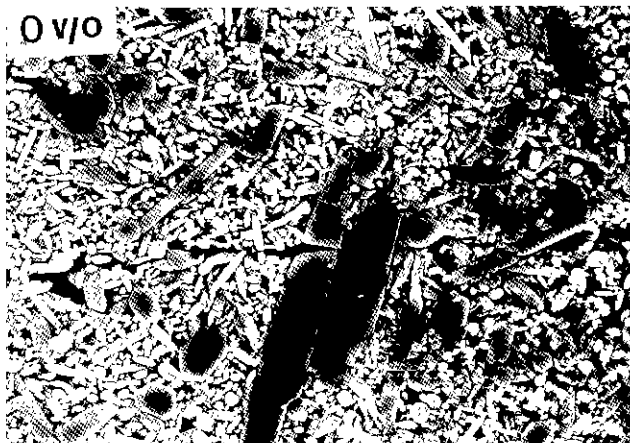
Electrical discharge machinable Si_3N_4 has been fabricated by adding TiN. When Si_3N_4 is sintered with a small amount of additives (3 wt%) at a relatively high temperature, the addition of TiN can improve the flexural strength and fracture toughness by suppressing exaggerated grain growth of Si_3N_4 . Si_3N_4 containing 40 vol% of TiN showed a flexural strength and fracture toughness comparable to those of monolithic Si_3N_4 , and a low electrical resistivity enough to give good electrical discharge machinability.

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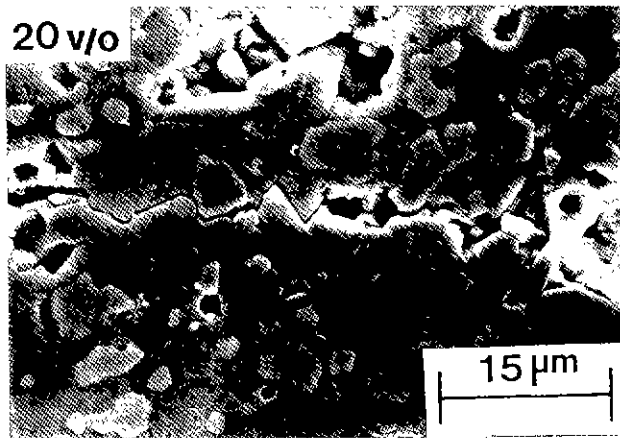
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References

1. P. Popper, "Application of Silicon Nitride," Volumes 89-91 of Key Engineering Materials, pp. 719-723, Edited by M. J. Hoffman, P. F. Becher and G. Petzow, Trans Tech Publications, Brookfield (1994).
2. A. Bellosi, S. Guicciardi and A. Tampieri, "Development and Characterization of Electroconductive Si_3N_4 -TiN Composites," *J. Eur. Ceram. Soc.*, **9**, 82-83 (1992).
3. C. Martin, B. Cales, P. Vivier and P. Mathieu, "Electrical Discharge Machinable Ceramic Composites," *Mat. Sci. Eng.*, A109 351-356 (1989).
4. E. Kajimo, M. Honda, M. Higuchi, H. Takeuchi and T. Tanimura, "Electrical Discharge Machinable Si_3N_4 Ceramics," *Sumitomo Electr. Tech. Rev.*, **24**, 183 (1985).
5. N. Tanari, T. Kondo, K. Keno and Y. Toibana, "Electrical Discharge Machining of Si_3N_4 -SiC Whisker Composites," *J. Ceram. Soc. Jpn.*, **12**, 1231-1235 (1986).
6. B. R. Lawn and E. R. Fuller, "Equilibrium Penny-Like Cracks in Indentation Fracture," *J. Mater. Sci.*, **12**, 2016-2024 (1975).
7. N. Hirotsaki, Y. Akimine and M. Mitomo, "Microstructure Design by Selective Grain Growth of Si_3N_4 ," *Mat. Res. Symp. Proc.*, **287**, 405-410 (1993).



(a)



(b)

Fig. 5. Typical crack propagations of the Si_3N_4 -TiN composites induced by a Vickers indenter; (a) 0 v/o TiN and (b) 20 v/o TiN.

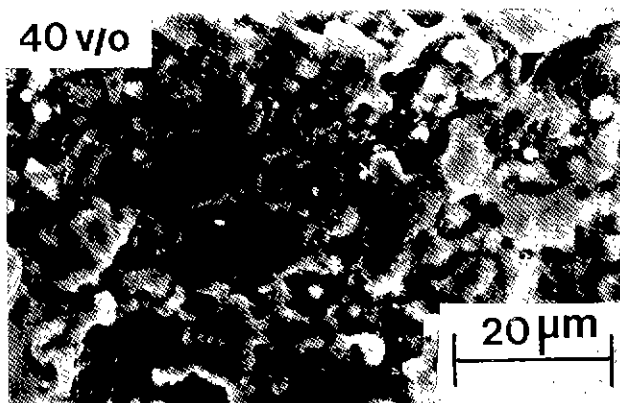


Fig. 6. Morphology of the electrical discharge machined surface of Si_3N_4 -40 vol% TiN composites showing melted and oxidized products of Si_3N_4 and TiN.

8. M. Mitomo and S. Uenosono, "Microstructure Development During Gas-Pressure Sintering of Silicon Nitride," *J. Am. Ceram. Soc.*, **75**[1], 103-108 (1992).
9. H. J. Kleebe, M. K. Cinibulk, I. Tanaka, J. Bruley, R. M. Cannon, D. R. Clarke, M. J. Hoffman and M. Ruhle, "High-Resolution Electron Microscopy Observations of Grain-Boundary Films in Silicon Nitride Ceramics," *Mat. Res. Symp. Proc.*, **287**, 65-78 (1993).
10. R. S. Tsai and R. Raj, "The Role of Grain-Boundary Sliding in Fracture of Hot-Pressed Si_3N_4 at High Temperatures," *J. Am. Ceram. Soc.*, **63**[9-10], 513-517 (1980).
11. H. J. Kleebe, "SiC and Si_3N_4 Materials with Improved Fracture Resistance," *J. Eur. Ceram. Soc.*, **10**, 151-159 (1992).
12. Y. G. Gogotsi and G. Grathwohl, "Creep of Silicon Nitride-Titanium Nitride Composites," *J. Mat. Sci.*, **28**, 4279-4287 (1993).
13. B. Lawn, "Fracture of Brittle Solids," pp. 332-334, Cambridge University Press, New York, 1993.
14. J. S. Song, Y. B. Son and C. H. Kim, "Mechanical Properties of the Pressureless Sintered Si_3N_4 -TiN Ceramic Composites," *J. Kor. Ceram. Soc.*, **26**[3], 409-415 (1989).
15. H. Takeuchi and E. Kamizo, "Electrical Discharge Machinable Si_3N_4 Ceramics," *Engineering Materials*, **32**[11], 96-100 (1986).